

FIG. 1

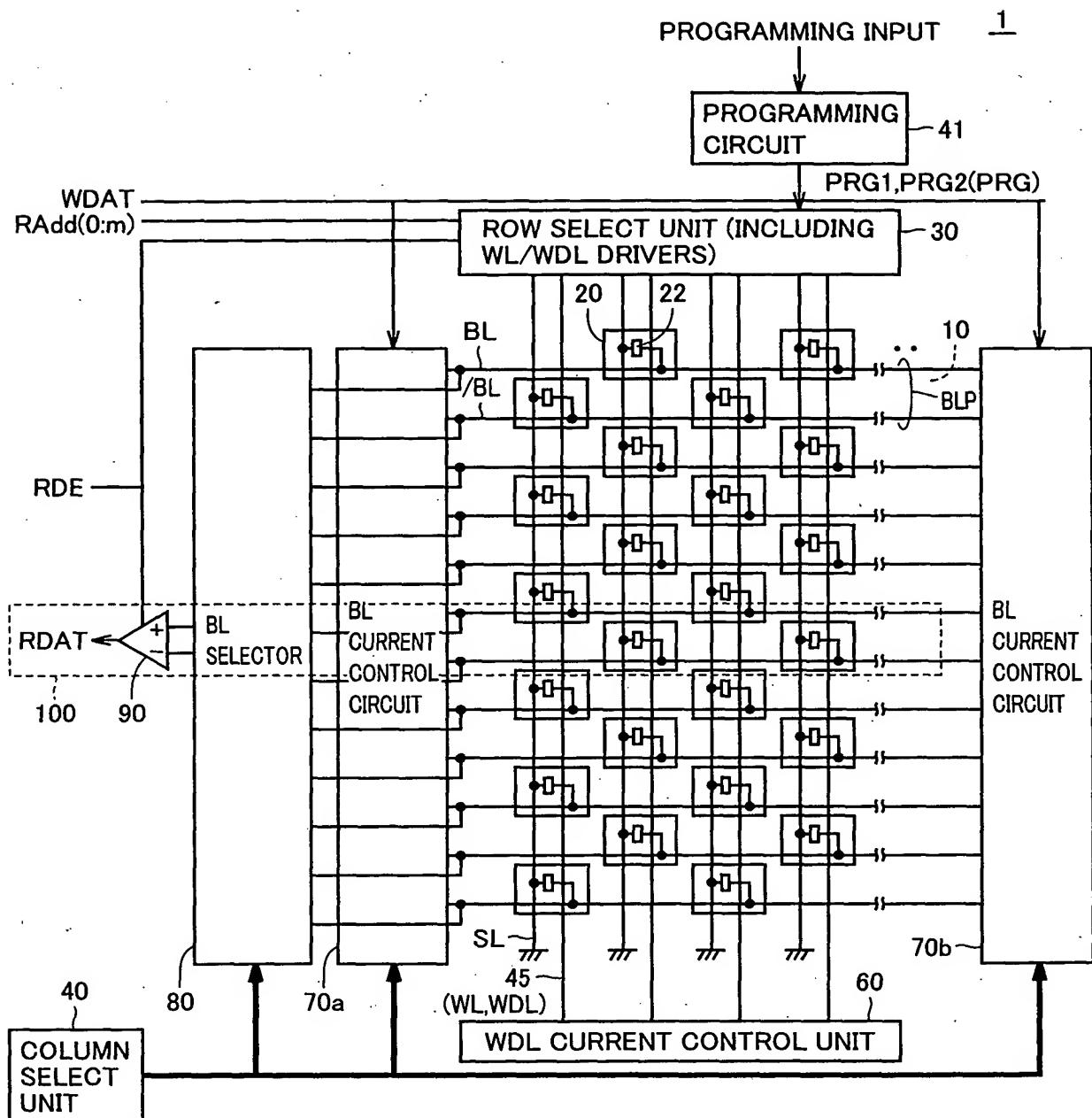


FIG.2

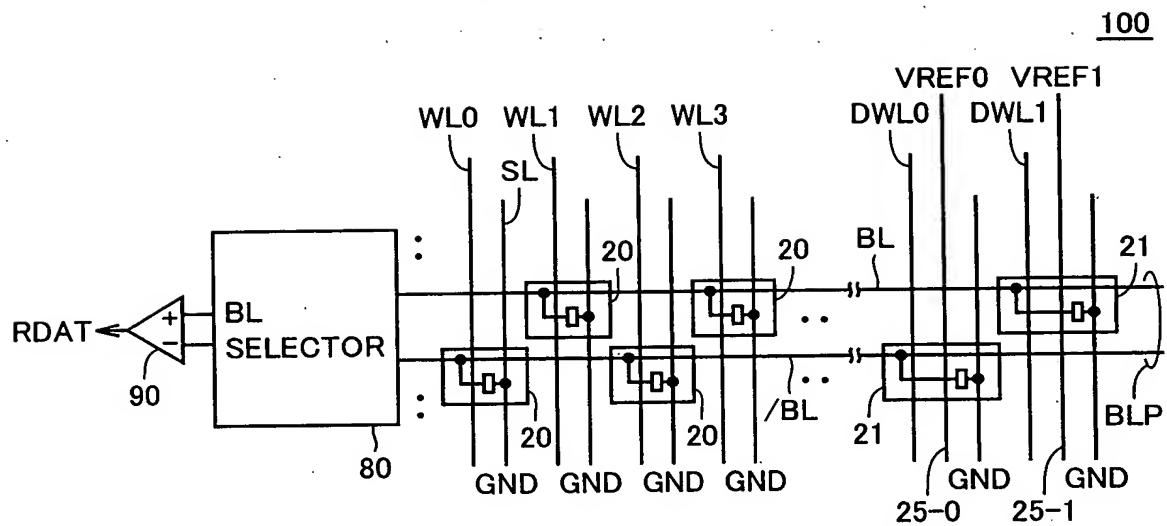


FIG.3

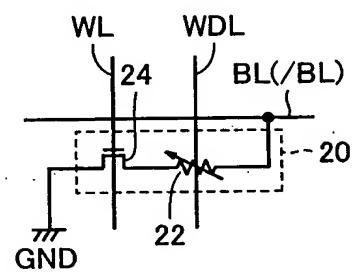


FIG.4

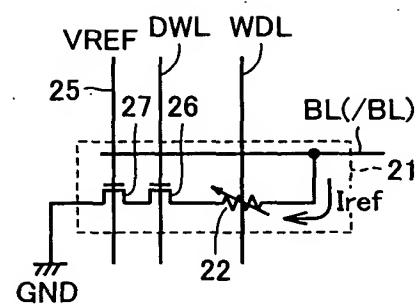


FIG.5

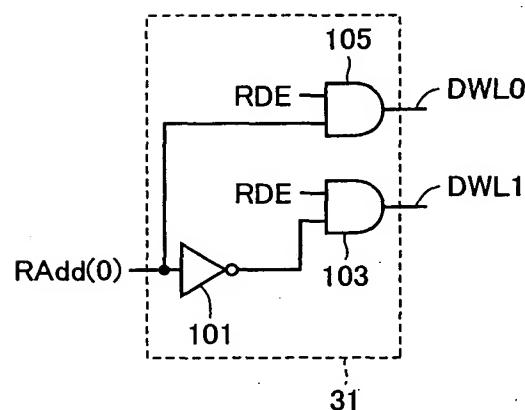


FIG.6

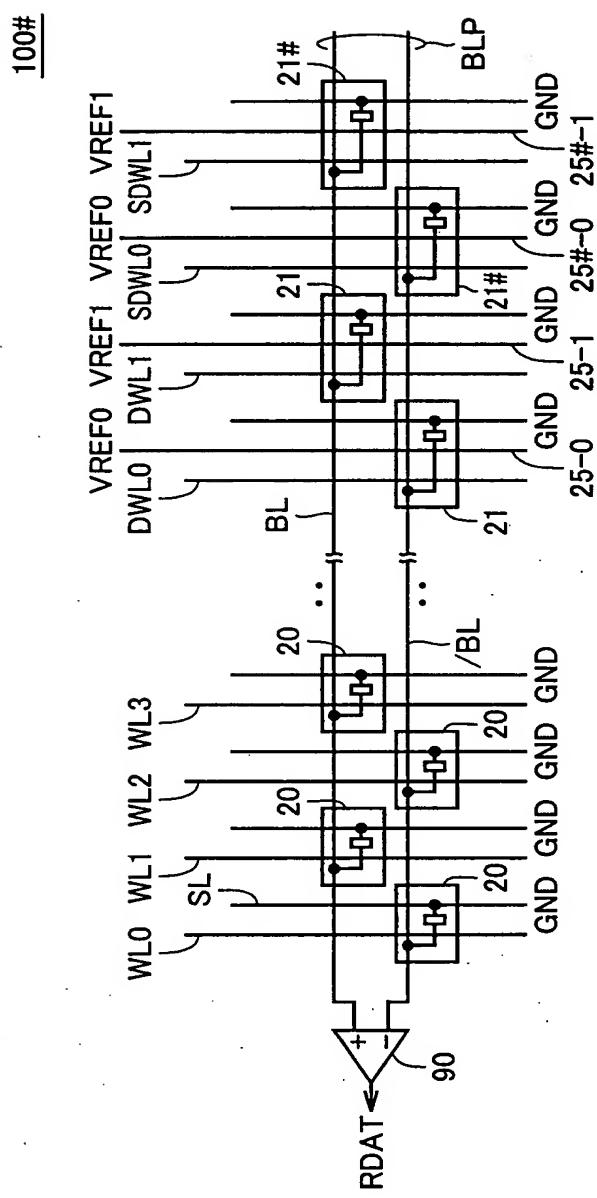


FIG.7

32

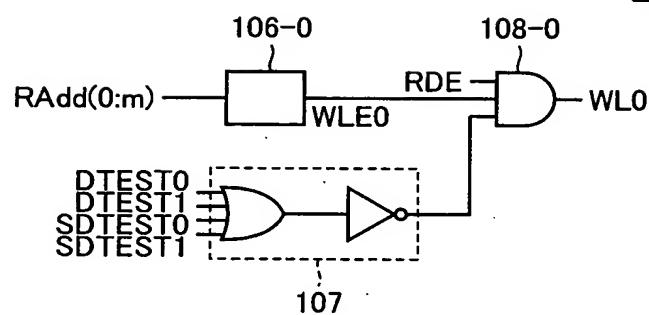


FIG.8

TEST CONTROL SIGNAL	TEST PATTERN			
	i)	ii)	iii)	iv)
DTEST0	H	L	L	L
DTEST1	L	H	L	L
SDTEST0	L	L	H	L
SDTEST1	L	L	L	H

REFERENCE CELL TEST MODE      SPARE REFERENCE CELL TEST MODE

FIG.9

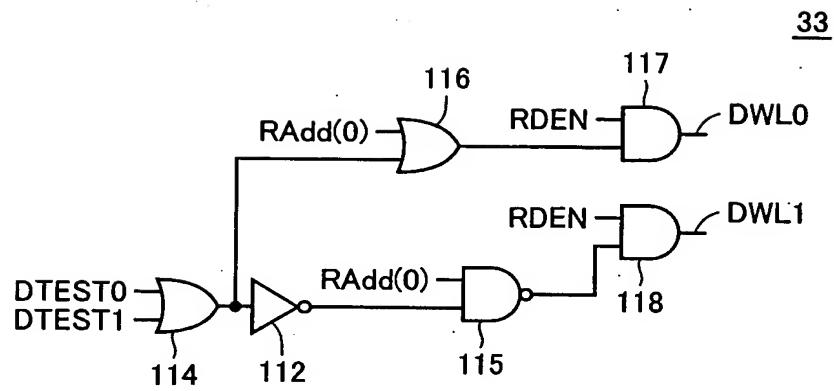


FIG.10

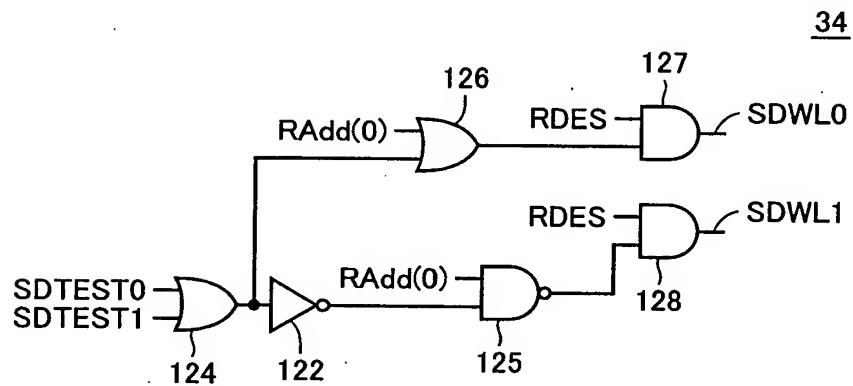


FIG.11

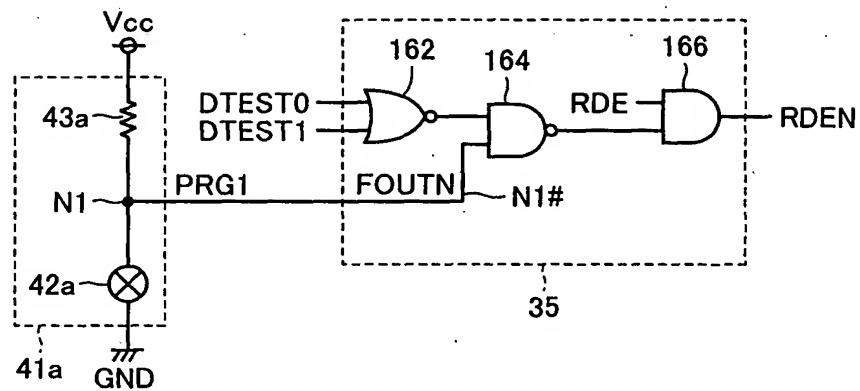


FIG.12

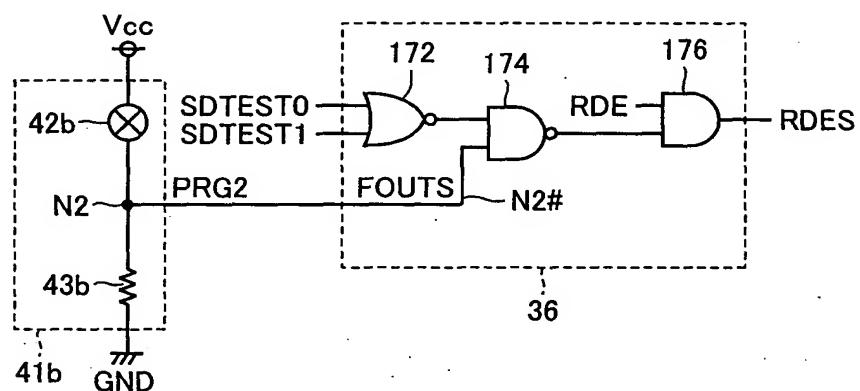


FIG.13

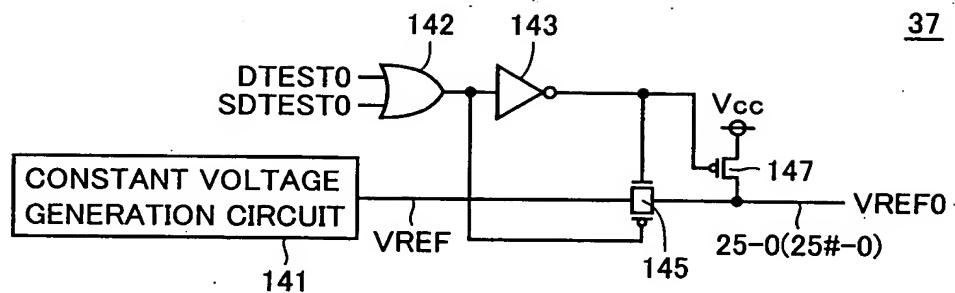


FIG.14

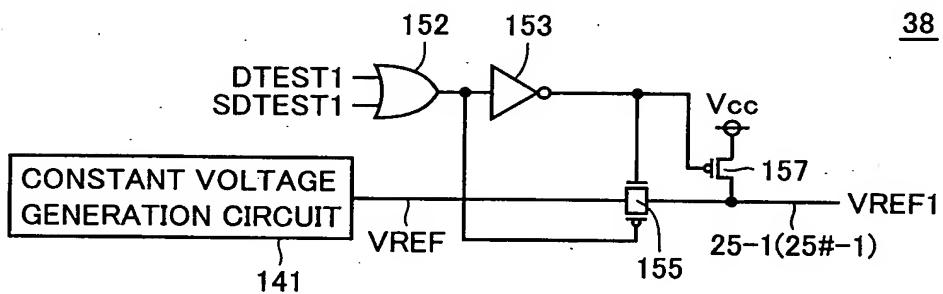


FIG.15

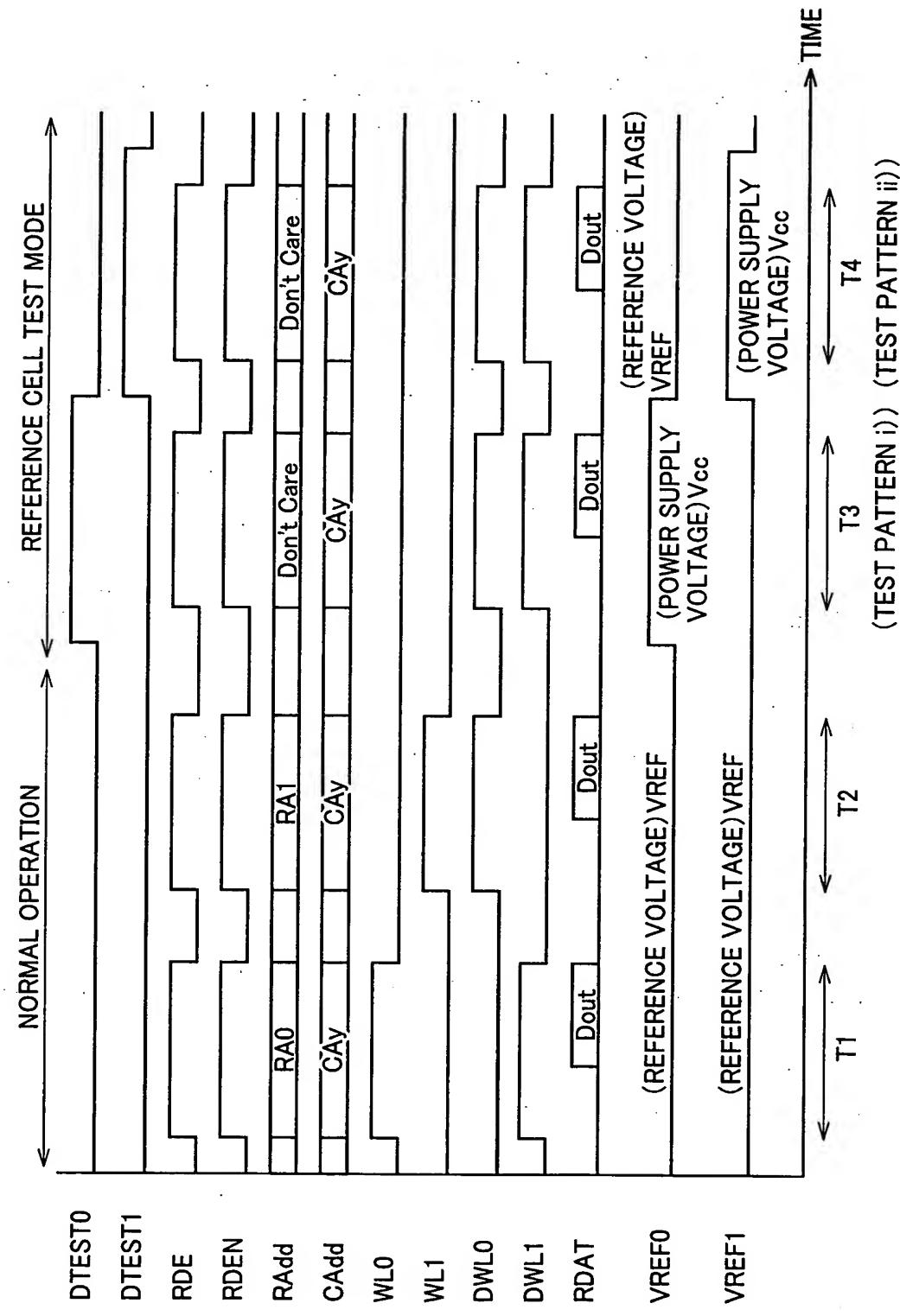


FIG 16

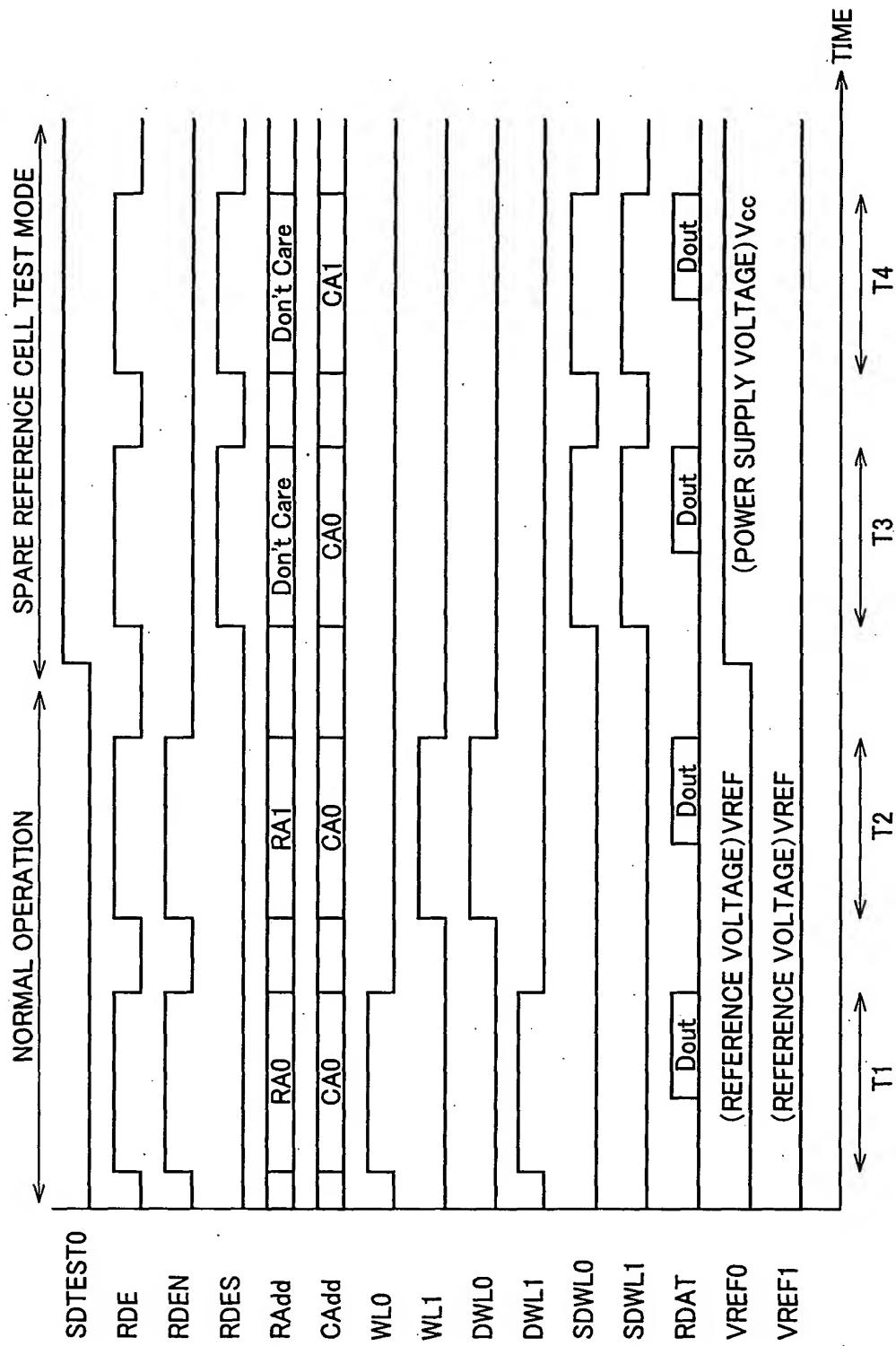


FIG.17

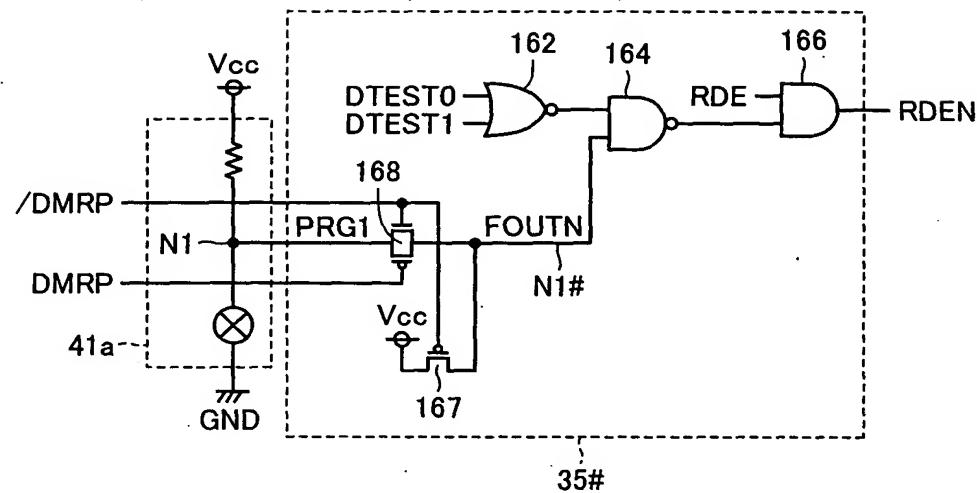


FIG.18

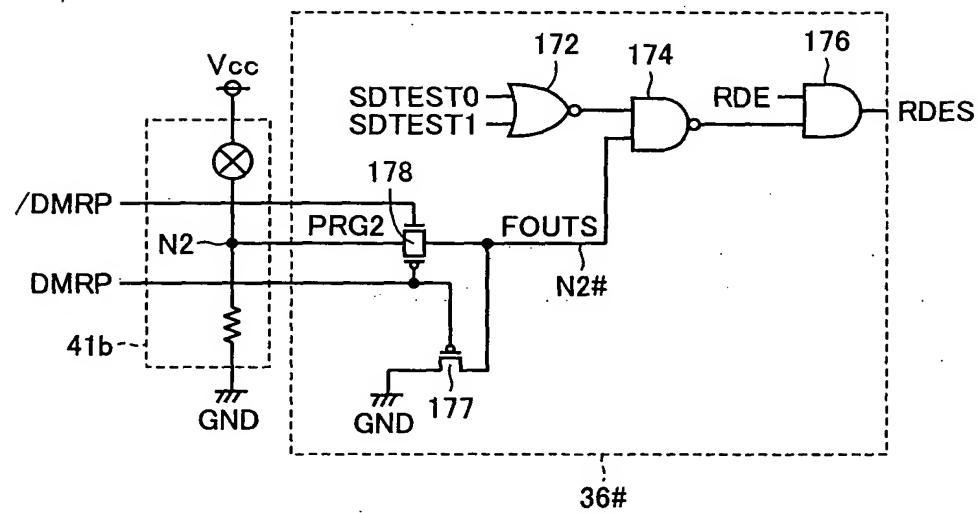


FIG.19

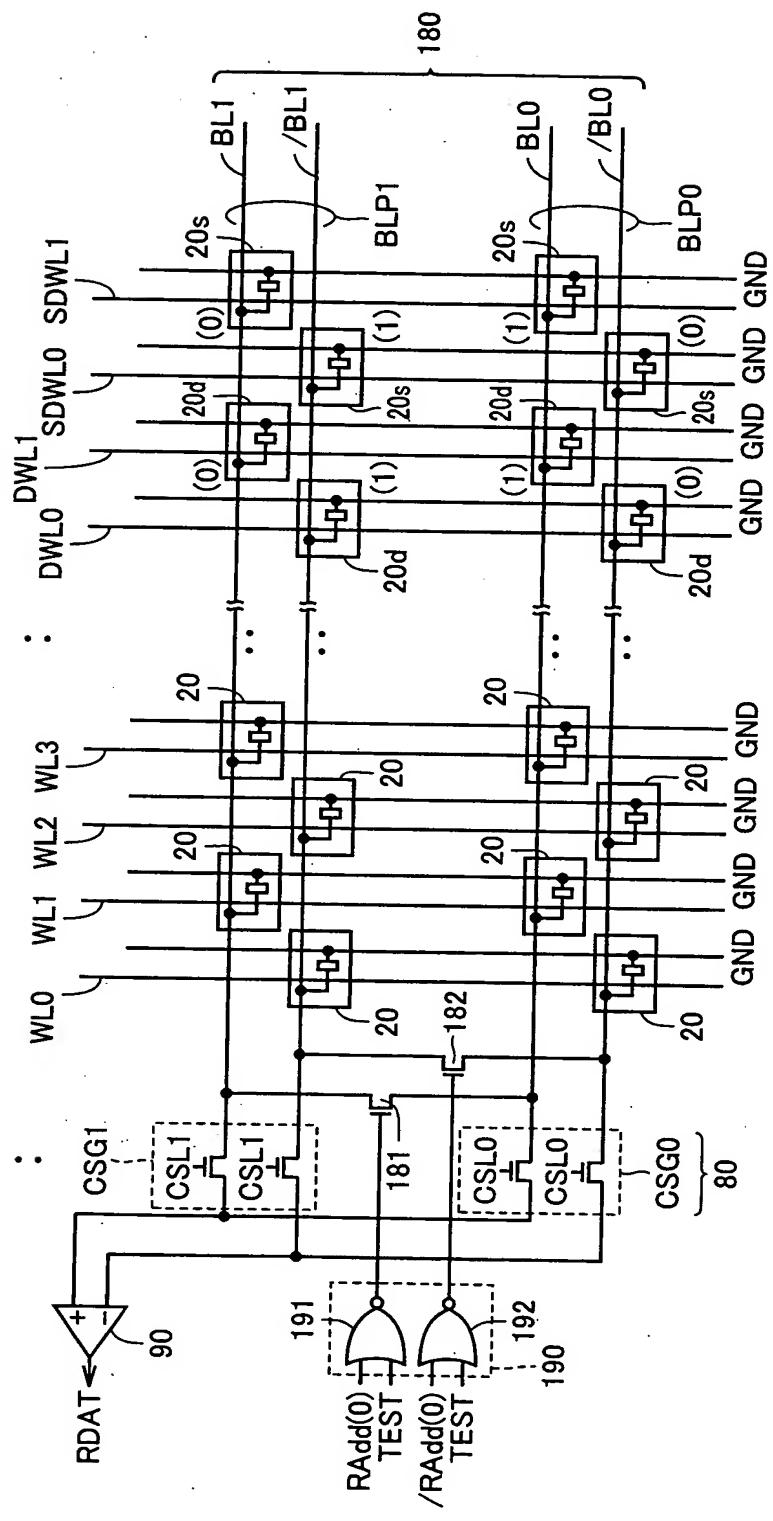


FIG.20

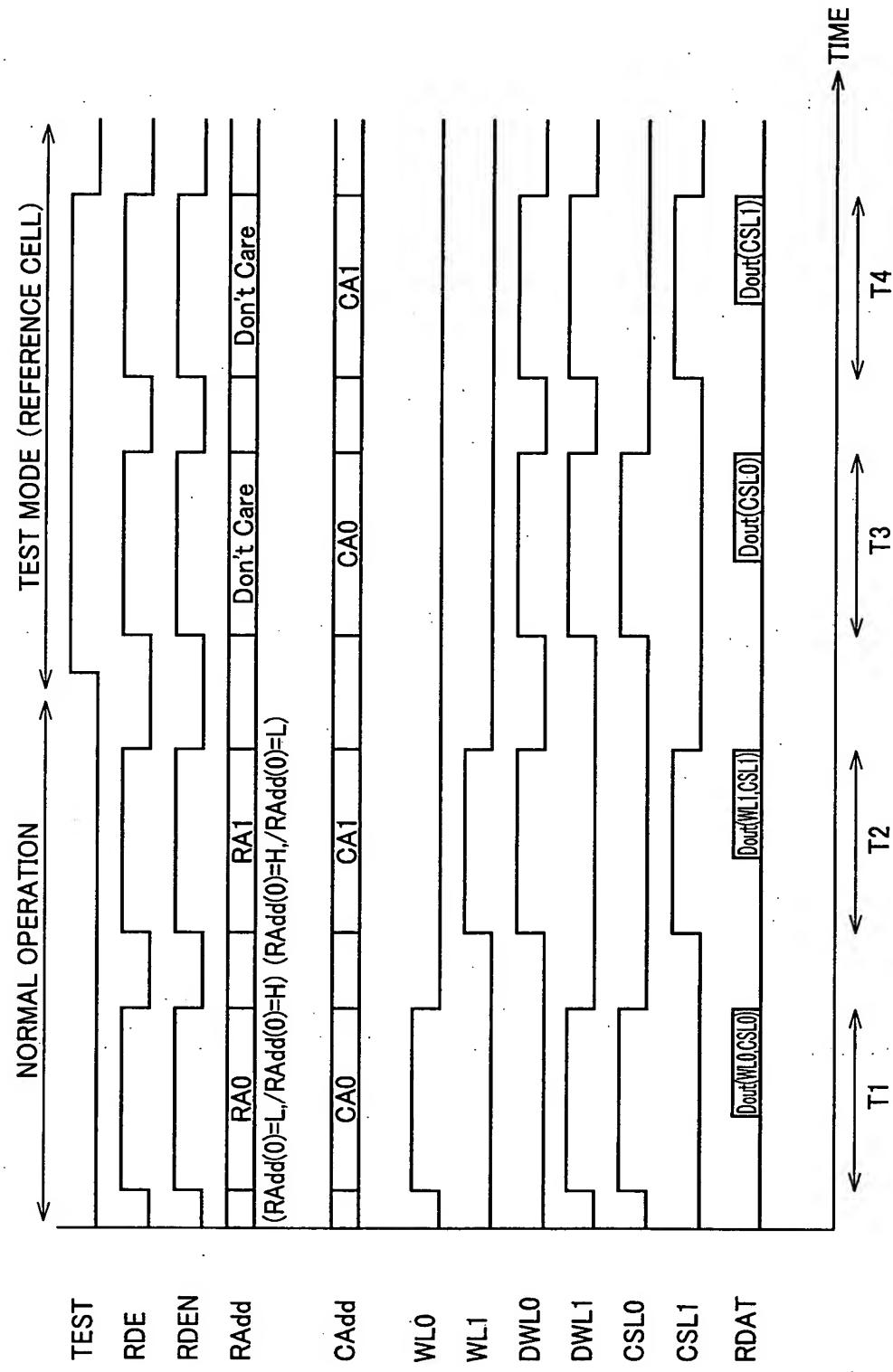


FIG.21A

NO DEFECT (FOR BOTH REGULAR MEMORY CELL & REFERENCE MEMORY CELL)

RAdd(0)	WL0,2,4,6,...	WL1,3,5,...	DWL0	DWL1	SDWL0	SDWL1
0(L)	SELECT	NON-SELECT	NON-SELECT	SELECT	NON-SELECT	NON-SELECT
1(H)	NON-SELECT	SELECT	SELECT	NON-SELECT	NON-SELECT	NON-SELECT

FIG.21B

REPLACEMENT OF REGULAR MEMORY CELL (REGULAR WORD LINE)

RAdd(0)	WL0,2,4,6,...	WL1,3,5,...	DWL0	DWL1	SDWL0	SDWL1
0(L)	SELECT	NON-SELECT	NON-SELECT	SELECT	SELECT	NON-SELECT
1(H)	NON-SELECT	SELECT	SELECT	NON-SELECT	NON-SELECT	SELECT

(NON-SELECTION OF DEFECTIVE WL ONLY)

(ONLY WHEN DEFECTIVE WL IS SELECTED)

FIG.21C

REPLACEMENT OF REFERENCE CELL (DUMMY WORD LINE)

RAdd(0)	WL0,2,4,6,...	WL1,3,5,...	DWL0	DWL1	SDWL0	SDWL1
0(L)	SELECT	NON-SELECT	NON-SELECT	NON-SELECT	NON-SELECT	SELECT
1(H)	NON-SELECT	SELECT	NON-SELECT	NON-SELECT	SELECT	NON-SELECT

FIG.22

